

Notice of References Cited	Application/Control No. 09/879,838	Applicant(s)/Patent Under Reexamination BECK ET AL.	
	Examiner Satish S. Rampuria	Art Unit 2124	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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NON-PATENT DOCUMENTS

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	U	Stegawski et al., A new virtual-instrumentation-base experimenting environment for undergraduate laboratories with application in research and manufacturing, 1997, IEEE, pg. 1418-1421
	V	Radhakrishnan et al., Characterization of Java applications at bytecode and ultra-SPARC machine code levels, 1999, IEEE, pg. 281-284
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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